



EVG NIL Technology Development

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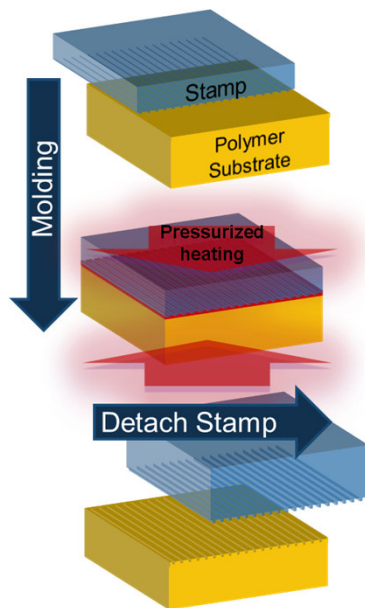


Nanoimprint Lithography at a Glance

Hot Embossing

Hard Stamp

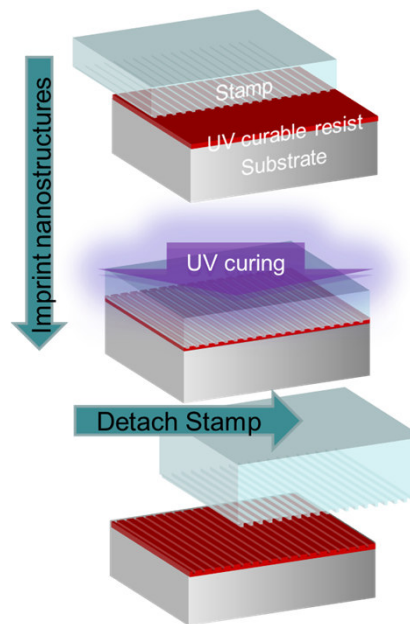
Polymer
Soft Stamp



UV-Nanoimprint Lithography (UV-NIL)

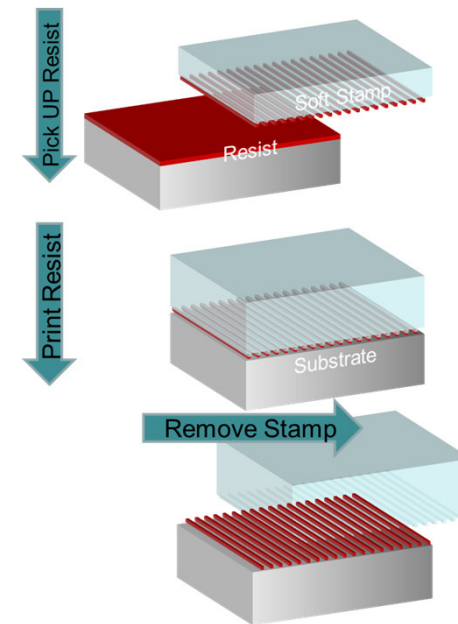
Transparent
Hard Stamp

Polymer
Soft Stamp



Micro Contact Printing (μ CP) Soft Lithography

Polymer
Soft Stamp



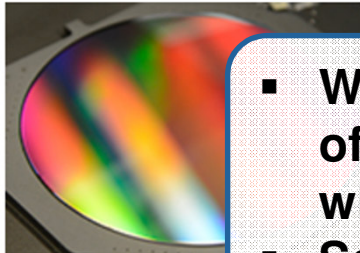
Evolution of EVG's Imprint Equipment



Unique Benefits of Nanoimprint Lithography

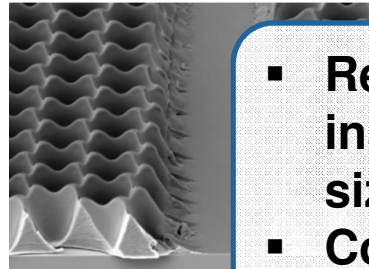


Large Area Nanopatterning



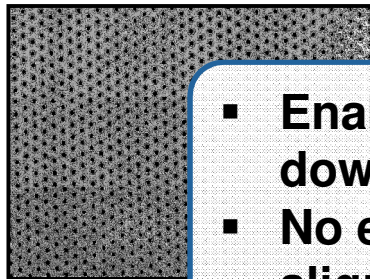
- Wafer level processing of nanostructures without stitching
- Scalable technology which is not limited by an optical system

3D Patterning



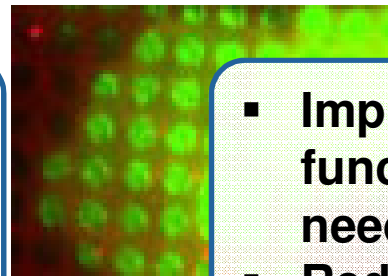
- Replication process is insensitive to shape, size & structure
- Complexity does not add manufacturing costs

Resolution \ll Alignment



- Enables highest resolution down to 20 nm and less
- No expensive precision alignment optics

Direct Patterning

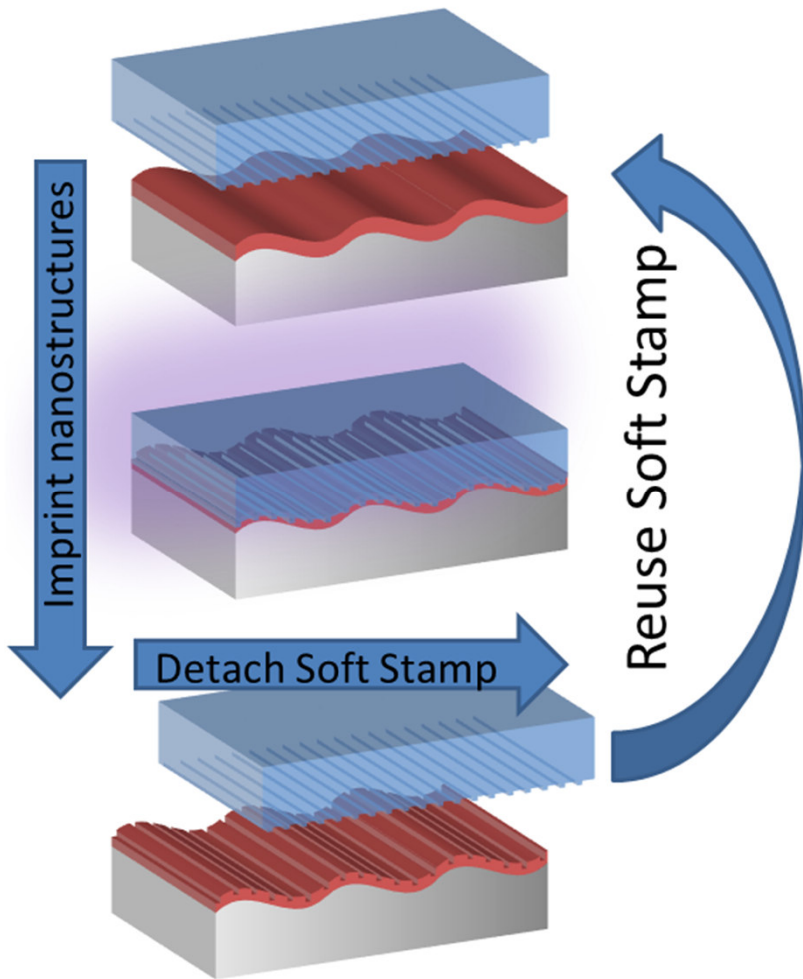


- Imprint materials can be functionalized to needed properties
- Reduces process steps significantly

SmartNIL[®] – Large Area Imprint



Conformal nanoimprinting

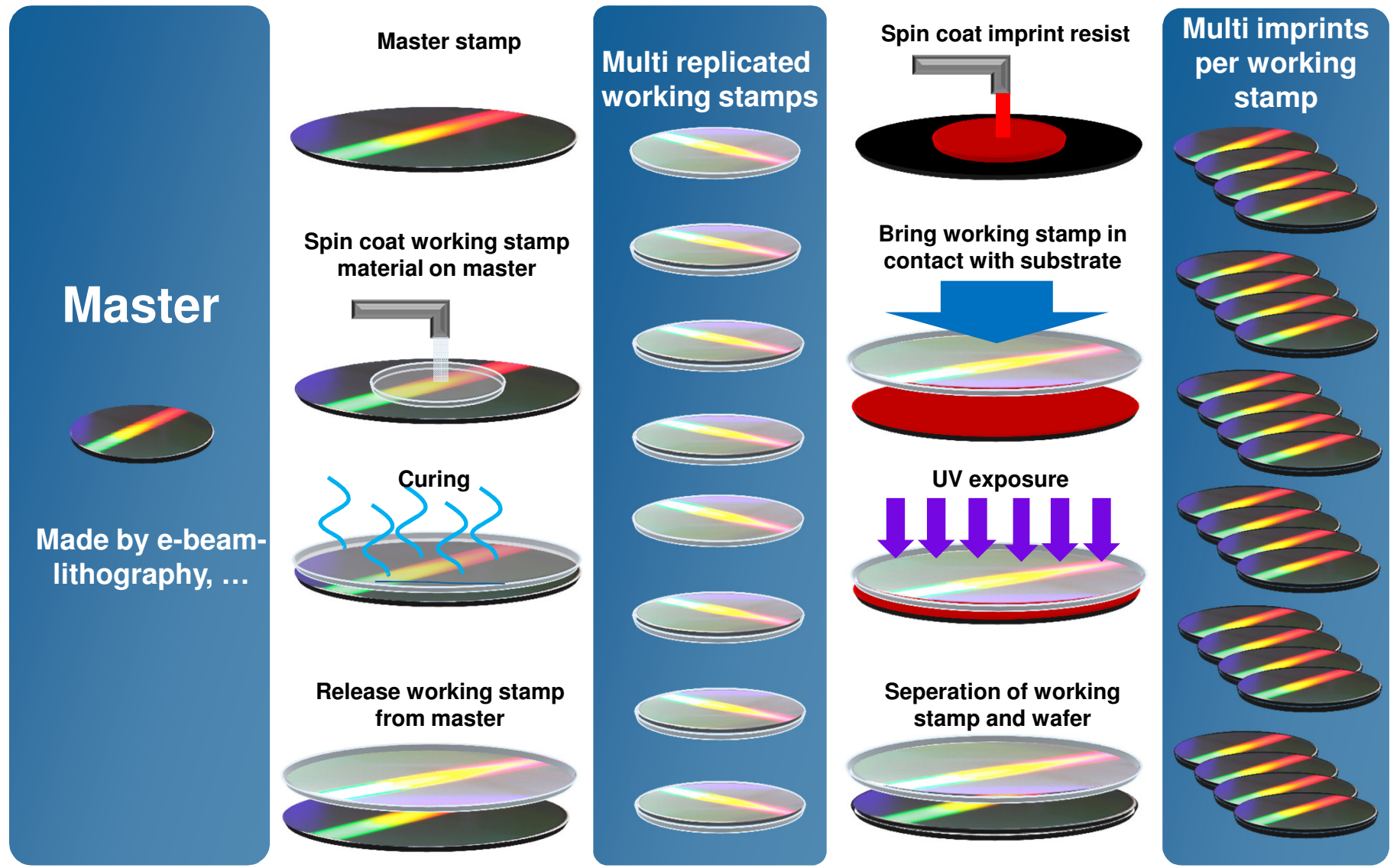


Basic elements of the technique:

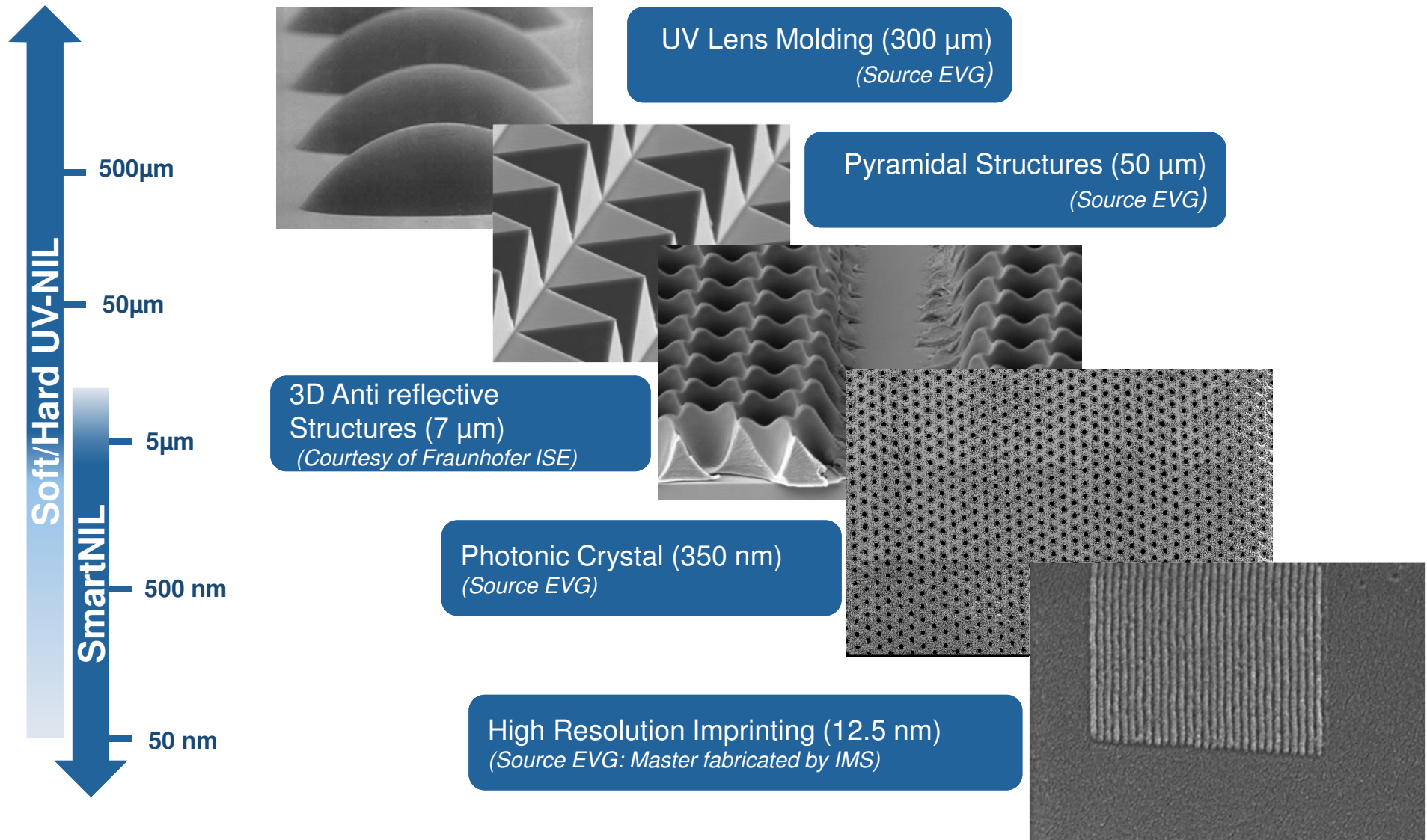
- Flexible UV-transparent molds
- Proprietary imprint tooling → **SmartNIL[®]**

Allows large area conformal imprints

Working Stamp - Improved Cost of Ownership (CoO)



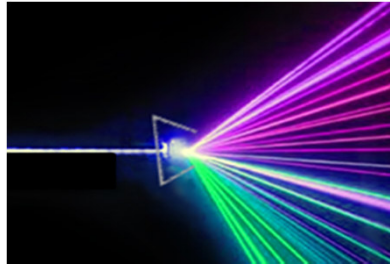
UV-NIL/SmartNIL[®] Resolution



Main Markets Today



Photonic Applications



Application Examples

Wire Grid Polarizer

DOE Pattern

Photonic Crystal

VR / AR

Bio-medical applications



Application Examples

Lab on a chip

Organ on a chip

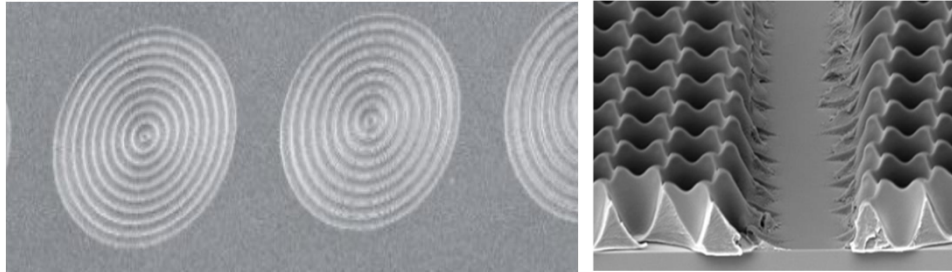
Chips with photonic structures

DNA Sequencing

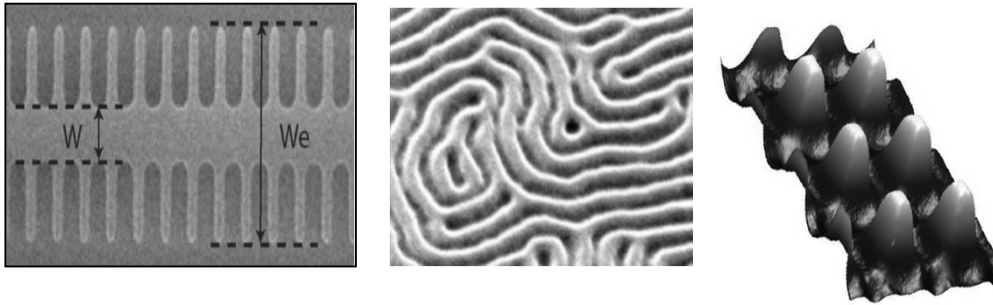
SmartNIL™ – Universal Capabilities



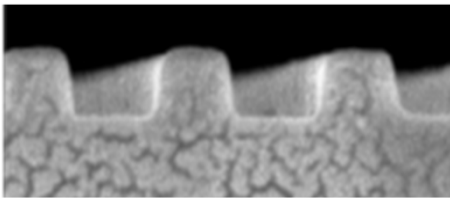
Diffractive Optical Elements



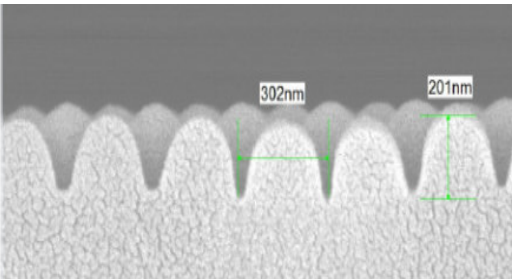
Holographic Structures



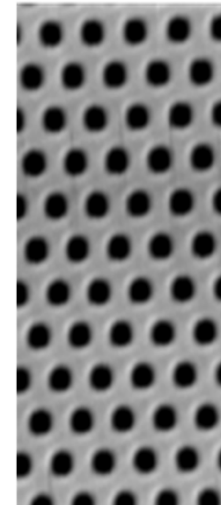
Optical Gratings



Anti Reflective Structures



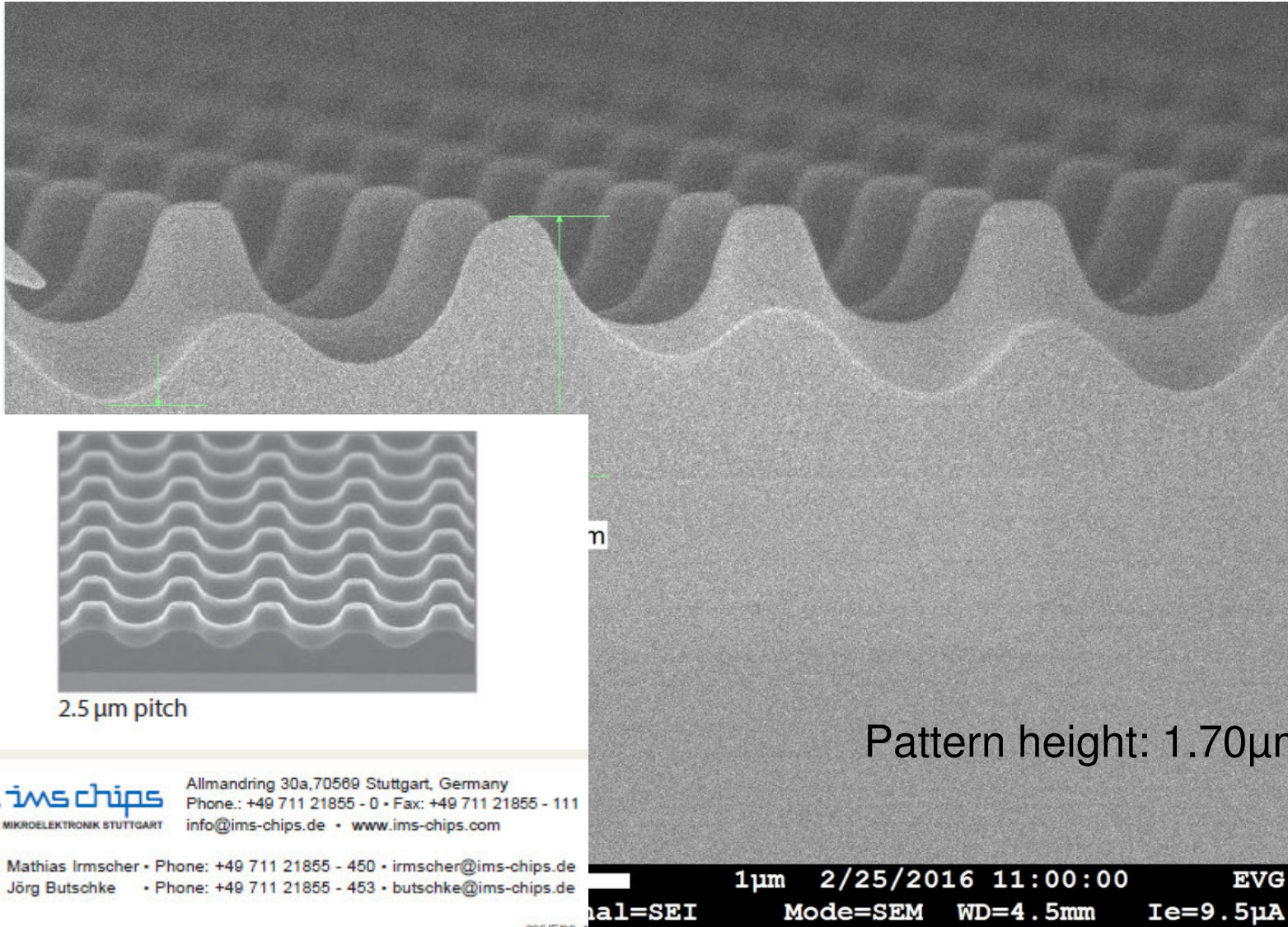
Plasmonic Structures



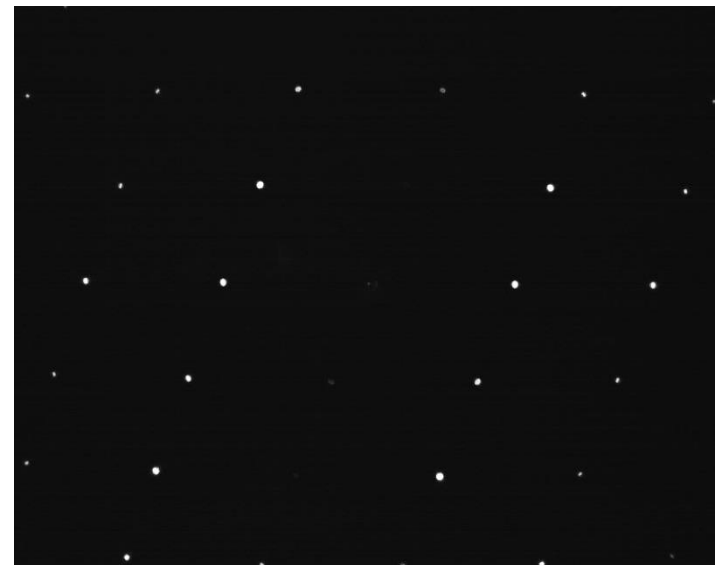
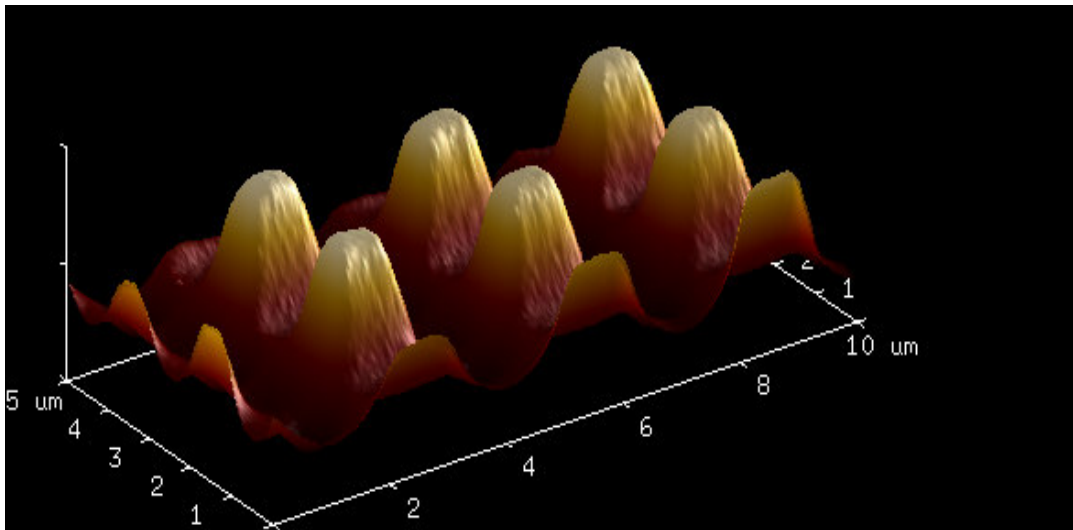
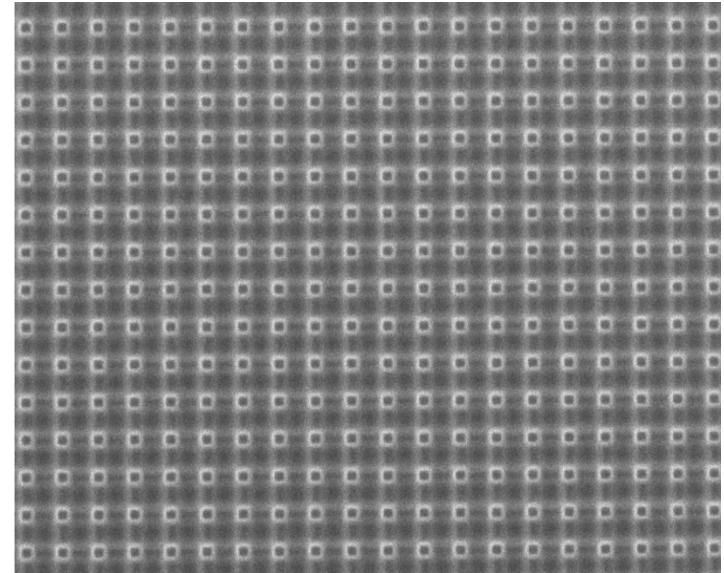
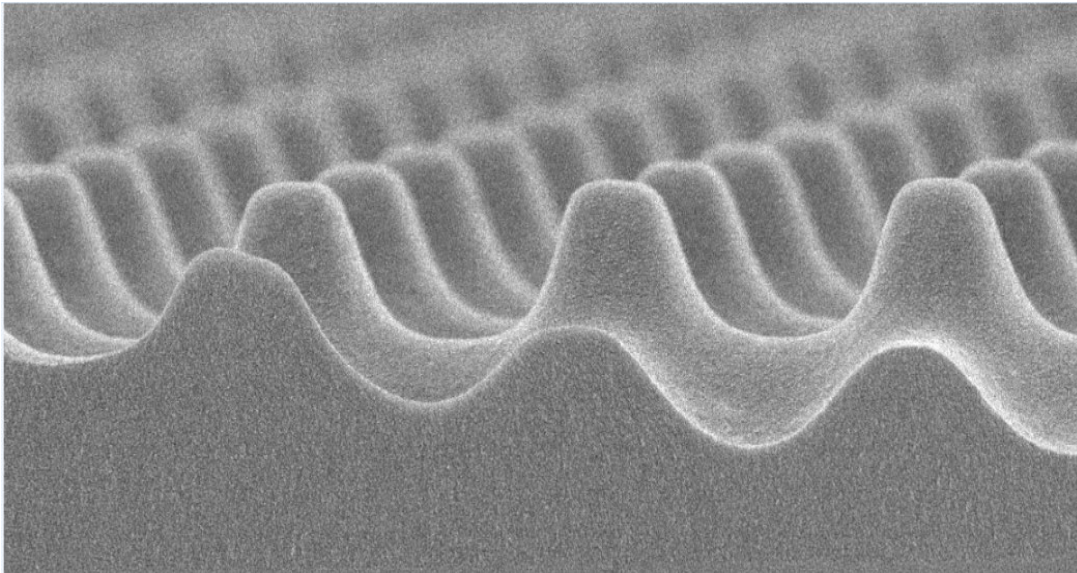
Arbitrary 3D Structure



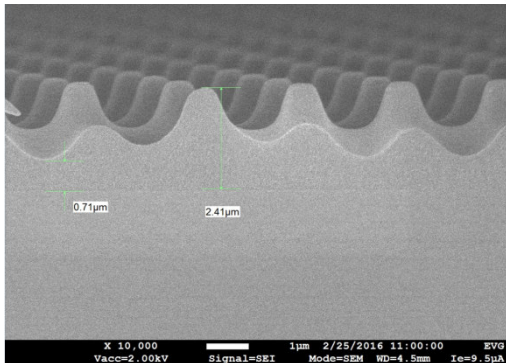
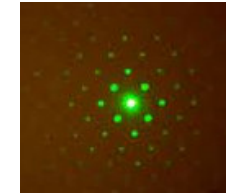
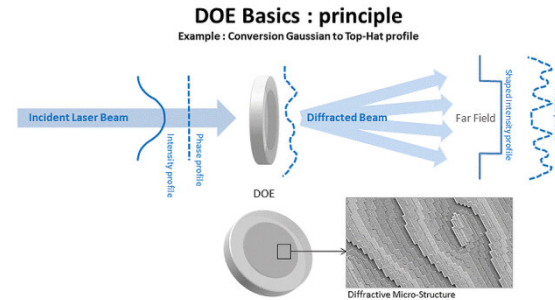
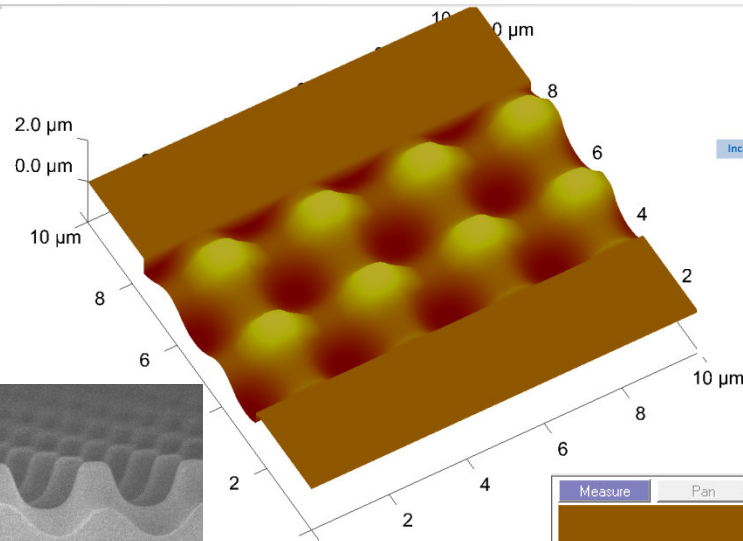
SEM – Imprint EVG NIL UV/A



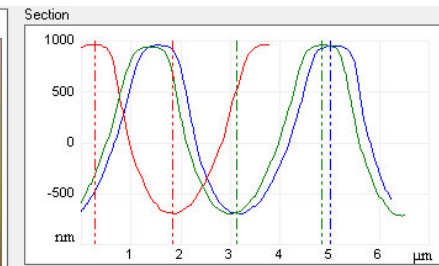
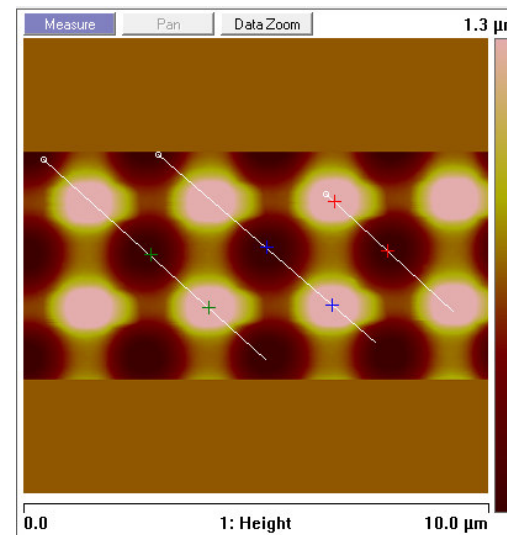
High Fidelity Patterns | DOE | IMS Structures



SmartNIL™ Template – Regular Pattern

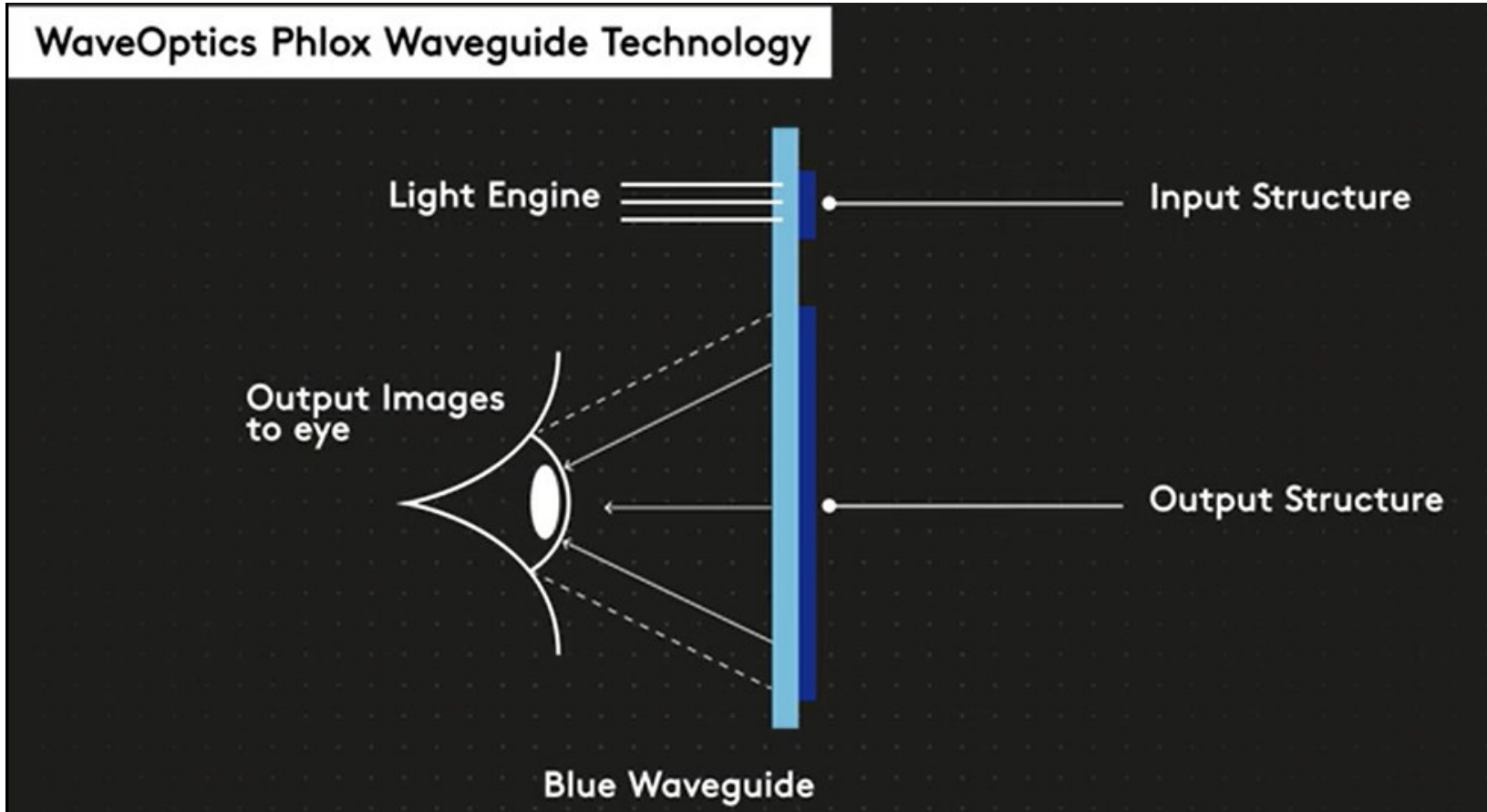


Position	#1	#2	#3	average
12:00	1,61	1,623	1,602	1,611667
03:00	1,603	1,616	1,604	1,607667
06:00	1,626	1,653	1,655	1,644667
09:00	1,639	1,662	1,636	1,645667
center	1,638	1,657	1,648	1,647667
				1,631467



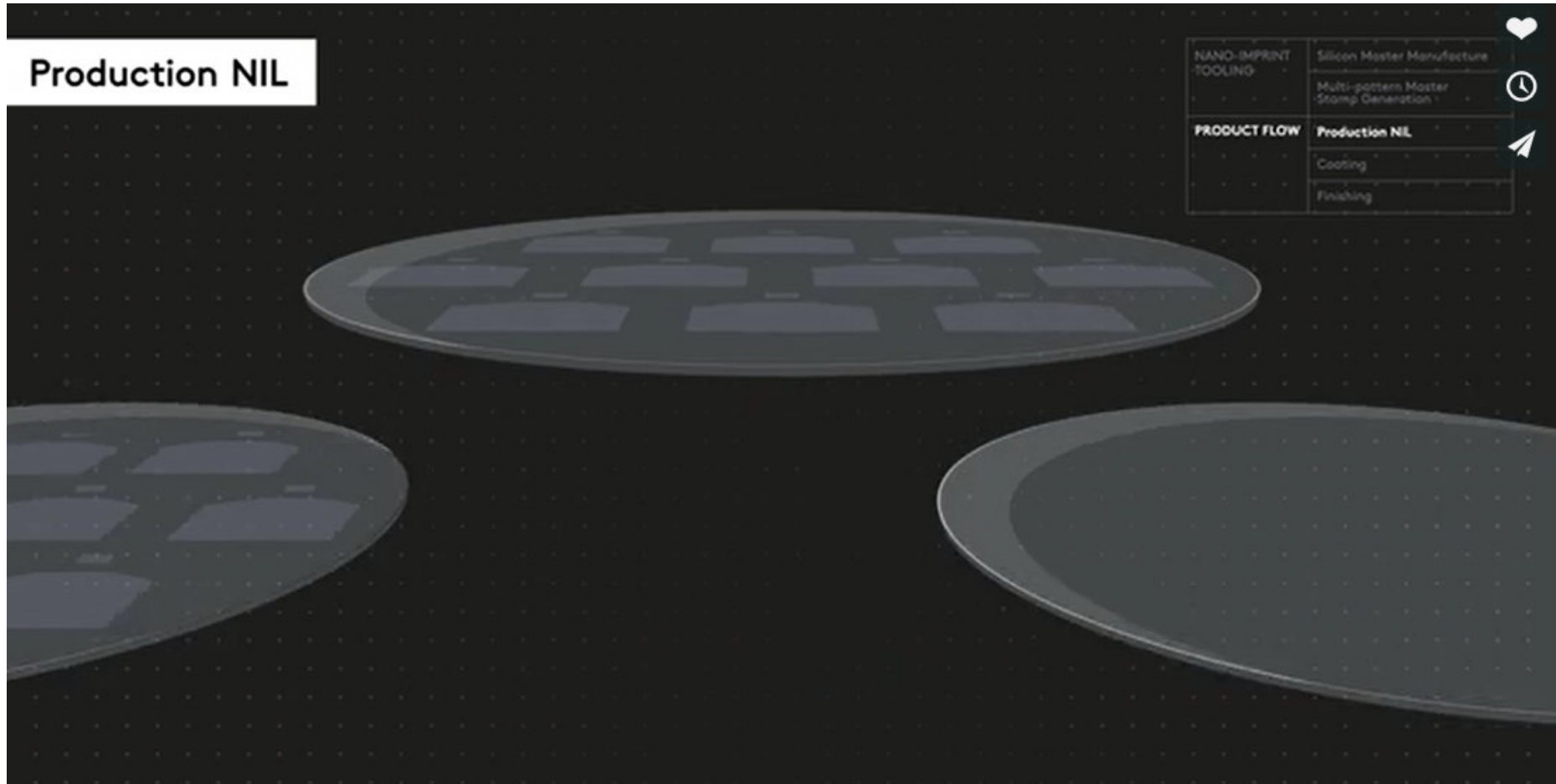
Pair	Horizontal Dist.	Vertical Dist.	Surface Dist.	Angle	Rmax	Rz	Rz Count	Rms	Ra (Freq cutoff)	Freq cutoff
0	1.884 (μm)	1638.27...	2.665 (μm)	41.0...	1598...	0.000 ...	0.000	603.9...	555.410 (nm)	0.316 ...
1	1.560 (μm)	-1657.4...	2.463 (μm)	-46...	1630...	0.000 ...	0.000	631.0...	583.209 (nm)	0.258 ...
2	1.727 (μm)	1648.26...	2.511 (μm)	43.6...	1720...	0.000 ...	0.000	599.5...	556.706 (nm)	0.303 ...





Source: Waveoptics Web Page - <http://enhancedworld.com/manufacturing/>

VR / AR Application



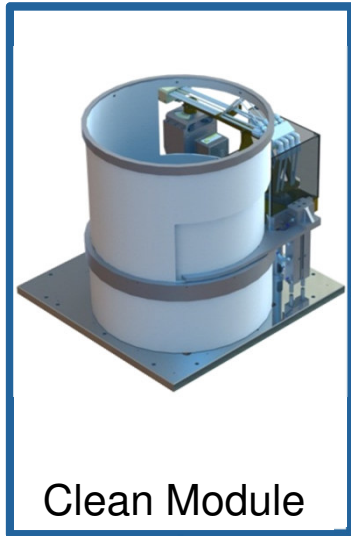
Source: Waveoptics Web Page - <http://enhancedworld.com/manufacturing/>

First fully integrated NIL track system worldwide

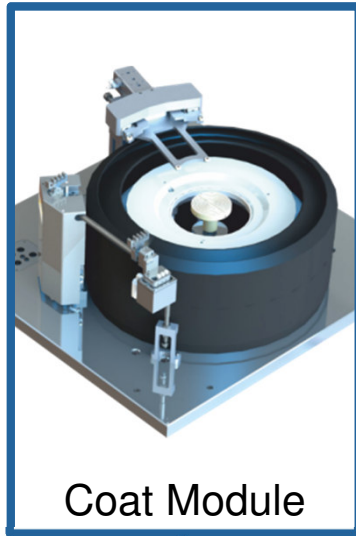
- Combines preprocessing and UV-NIL on a modular platform
- Redeems the long-term promise of nanoimprinting being a cost effective and high-volume alternative lithography technology
- Optimized solution for high throughput and low cost-of-ownership



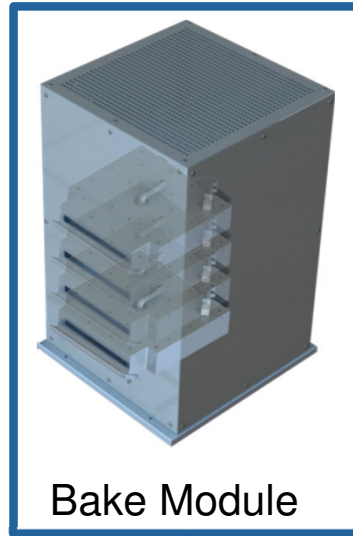
HERCULES® NIL



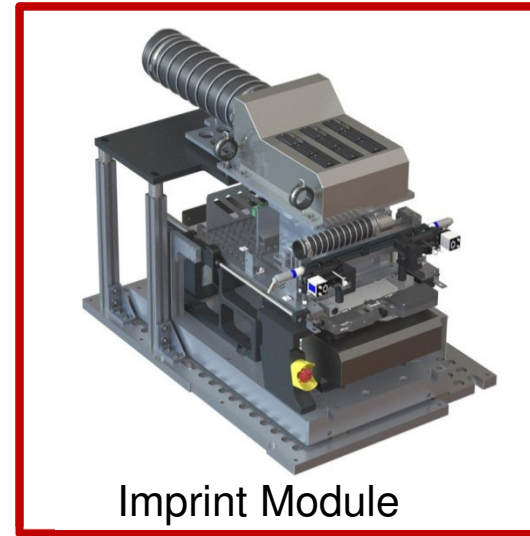
Clean Module



Coat Module



Bake Module



Imprint Module

Preprocessing
modules



The SmartNIL®
module is the heart of
the HERCULES® NIL



Gen 2 NIL System

Overview





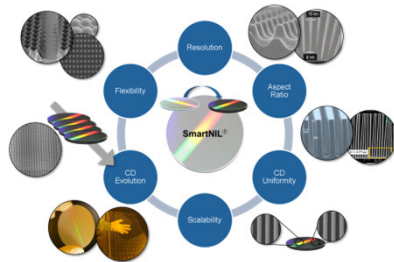
Key Takeaways



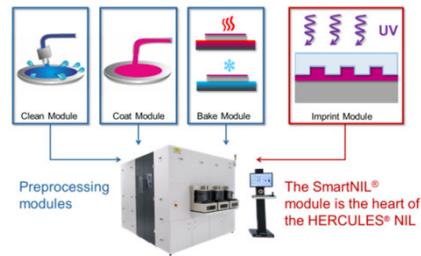
Wafer-level Nanoimprint Lithography

SmartNIL[®] is established for photonic, bio and non-CMOS manufacturing

Proven Capabilities



Equipment Readiness



Addressing Challenges Beyond



Targets

Enabling novel devices and applications

Fully CMOS compatible production line

Goals

Imprint Technology Improvement

Platform Improvements

Process Integration

Addressed Topics

Overlay, Yield, Material Influence

Automation, Process Monitoring, Performance

Etching, Deposition, Mix and match Lithography





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